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Test Procedure for the LC72725KVSGEVB Evaluation Board

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How to use:

- 1. Connect the power supply to VDD (TP2) and GND (TP1). $(+3.3\mathrm{V}$ to $+5.5\mathrm{V})$
- 2. Input composite signals to the BNC connector (CN1).
- 3. Toggle SW1 (RST) and SW2 (MODE) and SW3 (TEST) to "VSS" side.
- 4. If the LC72725KVS detects RDS signal in composite signal, RDS-ID output level turns "H". And the LED lights up.
- 5. Connect RDCL and RDDA with RDS encoder (as shown in Fig.2) to measure error rate.

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Appendix

Description of SW1 and SW2 and SW3:

(1)SW3 (TEST)

SW3=VDD: Standby mode is on when MODE (SW2) is switched to "VSS" side (Crystal circuit is stopped.).

SW3=VDD: LSI test mode is on when MODE (SW2) is switched to "VDD" side.

(Basically, customer cannot switch SW2 to VDD side.)

SW3=VSS: Once RDS signal is received, the signal is output from RDCL and RDDA, respectively. (2)SW2 (MODE)

SW2=VDD: Slave mode is on when TEST is switched to "VSS" side. RDS clock must be input to RDCL externally. RDS-ID/READY is set to READY output port.

SW2=VSS: Once the RDS signal is received, the signal is output from RDCL and RDDA, respectively. (3)SW1 (RST)

SW1=VDD: RDS-ID and internal buffer are reset. Once the RDS signal is received, the signal is output from RDCL and RDDA.

► The internal circuit is reset.

SW1=VSS: Once the RDS signal is received, the signal is output from RDCL and RDDA.

Fig.2 Bit error rate measurement



(*) RDS encoder(VP-7662A) no longer in production. An equivalent model is MEGURO MSG-2174.

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Reference data

FM Tuner LSI used LC01707PLF.

The bit error rate of LC72725KVS is as shown below.

